

Notice of References Cited	Application/Control No. 10/721,225		Applicant(s)/Patent Under Reexamination LUETZEN ET AL.	
	Examiner Binh X. Tran		Art Unit 1792	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,282,926	02-1994	Trah et al.	216/27
*	B	US-5,907,170	05-1999	Forbes et al.	257/296
*	C	US-6,455,369	09-2002	Forster et al.	438/249
*	D	US-6,703,273	03-2004	Wang et al.	438/243
*	E	US-7,141,506	11-2006	Endoh et al.	438/710
*	F	US-2001/0050436	12-2001	Sakao, Masato	257/758
*	G	US-2001/0016398	08-2001	KUDELKA et al.	438/427
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05109984 A	04-1993	Japan	YASUE, TAKAO	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.